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	AB	5,904,517	05/1999	Gardner et al.	•	438	197			
	AC	5,998,264	12/1999	Wu		438	260			
	AD	6,180,465 B1	01/2001	Gardner et al.		438	291			
4	AE	6,207,485 B1	03/2001	Gardner et al.		438	216			
wh	AF	6,548,854 B1	04/2003	Kizilyalli et al.	1	257	310			
	AG									
wy	АН	2003/0045060 A1	03/2003	Ahn et al.		438	287		1	
m	AJ	2003/0045078 A1	03/2003	Ahn et al.		438	585		- 1	
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	AM	Chang et al., S	ilicon surface	treatments in advanced M	AOS gate process	ing, Micro	<u></u> oelectro	onic Er	ngineerin	ıg,
Ny		(2004), pages	130-135						******	
	AN	Lemberger et a	II., Electrical c	haracterization and reliabi	ility aspects of zire	conium si	licate fi	lms ot	otained fi	rom
M			<i>p.</i>	Torono Linginosini	g (2004), pages 5	13-320		-		·
	AO	Lu et al., Effect	s of the TaN _x i	interface layer on doped to	antalum oxide hig	jh-k films,	VACU	UM (2	004), pa	ges 1-9
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pm	M	4,086,074	04/78	Minot et al.		438	61		
	AB	4,622,735	11/86	Shibata		438	303		
	AC	4,683,645	08/87	Naguib et al.		438	530		
	AD	4,693,910	09/87	Nakajima et al.		257	647		
	AE ,	4,766,090	08/88	Coquin et al.	•	438	222		
	AF	5,099,304	03/92	Takemura et al.		427	168		
	AG	5,236,865	08/93	Sandhu et al.		438	297		
	AH	- 5,444,024	08/95	Anjum et al.		4138	143		
ng	A	5,470,784	11/95	Anjum et al.		45	31		
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1	AB	6,037,239	03/00	Jennings		438	430		,
	AC	6,096,621	08/00 .	Jennings		438	404		
	AD	6,130,140	10/00	Gonzalez		4138	430		
	AE	6,133,105	10/00	Chen et al.		438	296		
	AF	6,133,116	10/00	Kim et al.		438	430		
	AG	6,156,674	12/00	Li et al.	· · · · · · · · · · · · · · · · · · ·	438	780		•
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AB	6,277,728 B1	08/01	Ahn et al.	_	438	619		
AC	6,291,363 B1	09/01	Yin et al.		138	769		
AD .	6,380,611 B1	04/02	Yin et al.		257			
AE	6,383,723 B1	05/02	lyer et al.		430	327		
A F	6,440,793 B1	08/02	Divakaruni et al.		438	243		
AG	6,465,325 B2	10/02	Ridley et al.		438	428		
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NB	M	2001/0006759 A1	07/01	Shipley, Jr. et al.		430	280.			
	AB	2002/0076879 A1	06/02	Lee et al.		4.38	241			
	AC	2002/0196651 A1	12/02	Weis		365	100			
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	AC	2003/0219942 A1	11/2003	Choi et al.		438	253		
	AD	2004/0245560 A1	12/2004	Pontoh et al.		257	309		
	AE	2004/0245559 A1	12/2004	Pontoh et al.		257	306	†	
	AF	2004/0046197 A1	03/2004	Basceri et al.		257	296		
	AG	2004/0043228 A1	03/2004	Derderian et al.		428	446		
	AH	2003/0213987 A1	11/2003	Basceri et al.	· -	257	296		
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